

# TC4027BP, TC4027BF, TC4027BFN

## TC4027B Dual J-K Master-Slave Flip Flop

TC4027B is J-K master-slave flip-flop having RESET and SET functions.

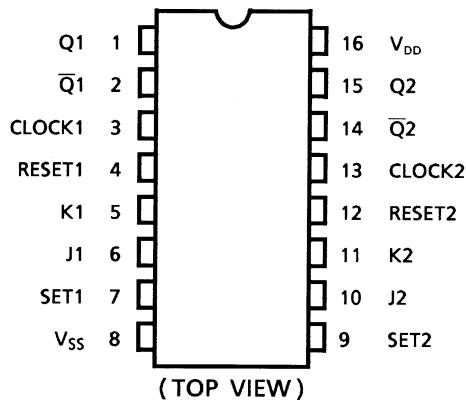
In the case of J-K made, when the clock input is given with both RESET and SET at "L", the output changes at rising edge of the clock according to the states of J and K.

When SET input is placed at "H", and RESET input is placed at "L", outputs become Q = "H", and  $\bar{Q}$  = "L".

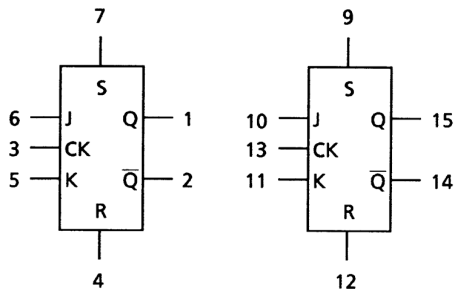
When RESET input is placed at "H", and SET input is placed at "L", outputs become Q = "L", and  $\bar{Q}$  = "H".

When both of RESET input and SET input are at "H", outputs become Q = "H" and  $\bar{Q}$  = "H".

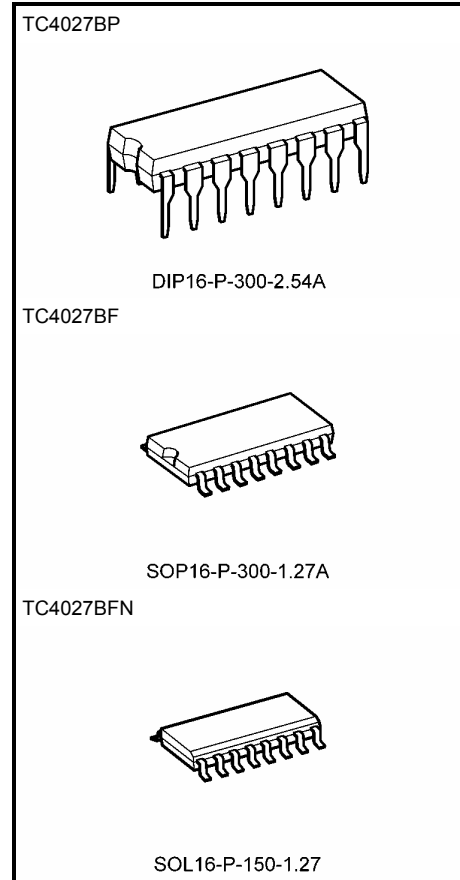
### Pin Assignment



### Block Diagram



Note: xxxFN (JEDEC SOP) is not available in Japan.



Weight	
DIP16-P-300-2.54A	: 1.00 g (typ.)
SOP16-P-300-1.27A	: 0.18 g (typ.)
SOL16-P-150-1.27	: 0.13 g (typ.)

## Truth Table

Inputs					Outputs	
RESET	SET	J	K	CLOCK $\Delta$	$Q_{n+1}$	$\bar{Q}_{n+1}$
L	H	*	*	*	H	L
H	L	*	*	*	L	H
H	H	*	*	*	H	H
L	L	L	L	$\uparrow$	$Q_n^*$	$Q_n^*$
L	L	L	H	$\uparrow$	L	H
L	L	H	L	$\uparrow$	H	L
L	L	H	H	$\uparrow$	$\bar{Q}_n^{**}$	$Q_n^{**}$
L	L	*	*	$\downarrow$	$Q_n^*$	$\bar{Q}_n^*$

\*: Don't care

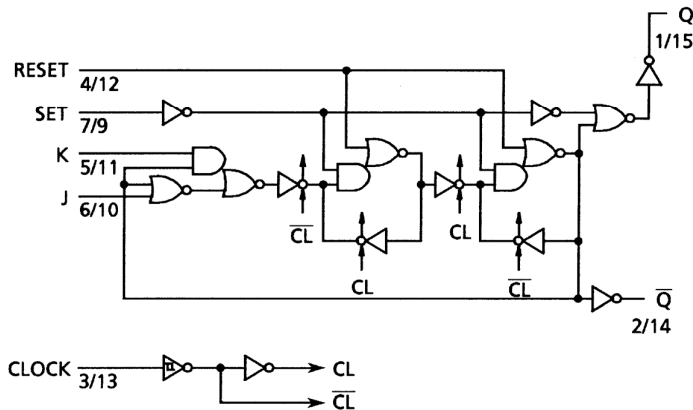
$\Delta$ : Level change

\*: No change

\*\* : Change

## Logic Diagram

### 1/2 TC4027B



## Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
DC supply voltage	$V_{DD}$	$V_{SS} - 0.5$ to $V_{SS} + 20$	V
Input voltage	$V_{IN}$	$V_{SS} - 0.5$ to $V_{DD} + 0.5$	V
Output voltage	$V_{OUT}$	$V_{SS} - 0.5$ to $V_{DD} + 0.5$	V
DC input current	$I_{IN}$	$\pm 10$	mA
Power dissipation	$P_D$	300 (DIP)/180 (SOIC)	mW
Operating temperature range	$T_{opr}$	-40 to 85	$^{\circ}C$
Storage temperature range	$T_{stg}$	-65 to 150	$^{\circ}C$

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## Operating Ranges ( $V_{SS} = 0\text{ V}$ ) (Note)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
DC supply voltage	$V_{DD}$	—	3	—	18	V
Input voltage	$V_{IN}$	—	0	—	$V_{DD}$	V

Note: The operating ranges must be maintained to ensure the normal operation of the device.  
Unused inputs must be tied to either  $V_{DD}$  or  $V_{SS}$ .

## Static Electrical Characteristics ( $V_{SS} = 0\text{ V}$ )

Characteristics	Sym- bol	Test Condition	$V_{DD}$ (V)	-40°C		25°C			85°C		Unit	
				Min	Max	Min	Typ.	Max	Min	Max		
High-level output voltage	$V_{OH}$	$ I_{OUT}  < 1\ \mu\text{A}$ $V_{IN} = V_{SS}, V_{DD}$	5	4.95	—	4.95	5.00	—	4.95	—	V	
			10	9.95	—	9.95	10.00	—	9.95	—		
			15	14.95	—	14.95	15.00	—	14.95	—		
Low-level output voltage	$V_{OL}$	$ I_{OUT}  < 1\ \mu\text{A}$ $V_{IN} = V_{SS}, V_{DD}$	5	—	0.05	—	0.00	0.05	—	0.05	V	
			10	—	0.05	—	0.00	0.05	—	0.05		
			15	—	0.05	—	0.00	0.05	—	0.05		
Output high current	$I_{OH}$	$V_{OH} = 4.6\text{ V}$ $V_{OH} = 2.5\text{ V}$ $V_{OH} = 9.5\text{ V}$ $V_{OH} = 13.5\text{ V}$ $V_{IN} = V_{SS}, V_{DD}$	5	-0.61	—	-0.51	-1.0	—	-0.42	—	mA	
			5	-2.50	—	-2.10	-4.0	—	-1.70	—		
			10	-1.50	—	-1.30	-2.2	—	-1.10	—		
			15	-4.00	—	-3.40	-9.0	—	-2.80	—		
Output low current	$I_{OL}$	$V_{OL} = 0.4\text{ V}$ $V_{OL} = 0.5\text{ V}$ $V_{OL} = 1.5\text{ V}$ $V_{IN} = V_{SS}, V_{DD}$	5	0.61	—	0.51	1.2	—	0.42	—	mA	
			10	1.50	—	1.30	3.2	—	1.10	—		
			15	4.00	—	3.40	12.0	—	2.80	—		
			—	—	—	—	—	—	—	—		
Input high voltage	$V_{IH}$	$V_{OUT} = 0.5\text{ V}, 4.5\text{ V}$ $V_{OUT} = 1.0\text{ V}, 9.0\text{ V}$ $V_{OUT} = 1.5\text{ V}, 13.5\text{ V}$ $ I_{OUT}  < 1\ \mu\text{A}$	5	3.5	—	3.5	2.75	—	3.5	—	V	
			10	7.0	—	7.0	5.50	—	7.0	—		
			15	11.0	—	11.0	8.25	—	11.0	—		
			—	—	—	—	—	—	—	—		
Input low voltage	$V_{IL}$	$V_{OUT} = 0.5\text{ V}, 4.5\text{ V}$ $V_{OUT} = 1.0\text{ V}, 9.0\text{ V}$ $V_{OUT} = 1.5\text{ V}, 13.5\text{ V}$ $ I_{OUT}  < 1\ \mu\text{A}$	5	—	1.5	—	2.25	1.5	—	1.5	V	
			10	—	3.0	—	4.50	3.0	—	3.0		
			15	—	4.0	—	6.75	4.0	—	4.0		
			—	—	—	—	—	—	—	—		
Input current	"H" level	$I_{IH}$	$V_{IH} = 18\text{ V}$	18	—	0.1	—	$10^{-5}$	0.1	—	1.0	$\mu\text{A}$
	"L" level	$I_{IL}$	$V_{IL} = 0\text{ V}$	18	—	-0.1	—	$-10^{-5}$	-0.1	—	-1.0	
Quiescent supply current	$I_{DD}$	$V_{IN} = V_{SS}, V_{DD}$ (Note)	5	—	1	—	0.002	1	—	30	$\mu\text{A}$	
			10	—	2	—	0.004	2	—	60		
			15	—	4	—	0.008	4	—	120		

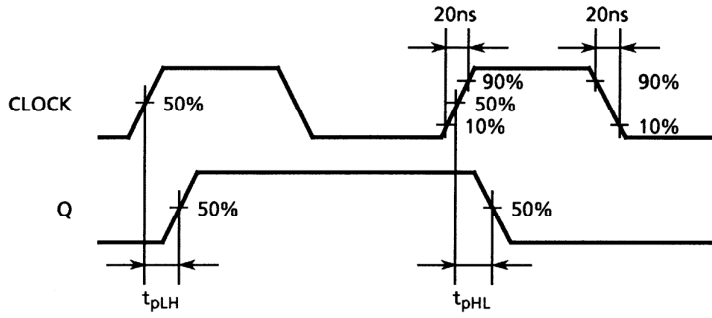
Note: All valid input combinations.

**Dynamic Electrical Characteristics (Ta = 25°C, VSS = 0 V, CL = 50 pF)**

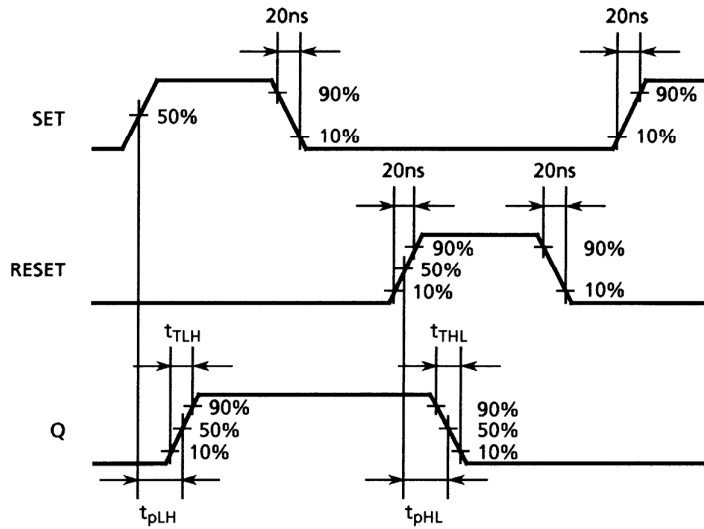
Characteristics	Symbol	Test Condition	VDD (V)	Min	Typ.	Max	Unit
Output transition time (low to high)	t <sub>TLH</sub>	—	5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Output transition time (high to low)	t <sub>THL</sub>	—	5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Propagation delay time (CLOCK-Q, $\bar{Q}$ )	t <sub>pLH</sub> t <sub>pHL</sub>	—	5	—	150	300	ns
			10	—	75	130	
			15	—	60	90	
Propagation delay time (SET, RESET-Q, $\bar{Q}$ )	t <sub>pLH</sub> t <sub>pHL</sub>	—	5	—	120	300	ns
			10	—	60	130	
			15	—	45	90	
Max clock frequency	f <sub>CL</sub>	—	5	3.5	8	—	MHz
			10	8.0	16	—	
			15	12.0	20	—	
Max clock input rise time Max clock input fall time	t <sub>rCL</sub> t <sub>fCL</sub>	—	5	No limit			μs
			10				
			15				
Min pulse width (SET, RESET)	t <sub>w</sub>	—	5	—	60	180	ns
			10	—	35	80	
			15	—	25	50	
Min clock pulse width	t <sub>w</sub>	—	5	—	60	140	ns
			10	—	35	60	
			15	—	25	40	
Min set-up time (J, K-CLOCK)	t <sub>SU</sub>	—	5	—	30	140	ns
			10	—	10	50	
			15	—	5	35	
Min hold time (J, K-CLOCK)	t <sub>H</sub>	—	5	—	—	140	ns
			10	—	—	50	
			15	—	—	35	
Min removal time (SET, RESET-CLOCK)	t <sub>rem</sub>	—	5	—	—	40	ns
			10	—	—	20	
			15	—	—	15	
Input capacitance	C <sub>IN</sub>	—	—	5	7.5	pF	

**Waveforms for Measurement of Dynamic Characteristics**

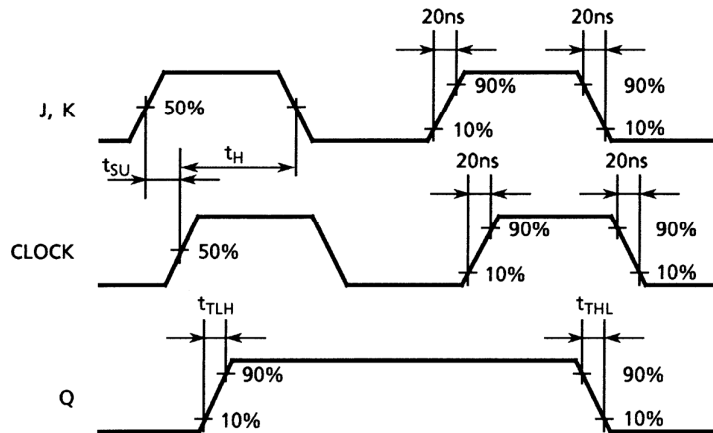
**Waveform 1**



**Waveform 2**



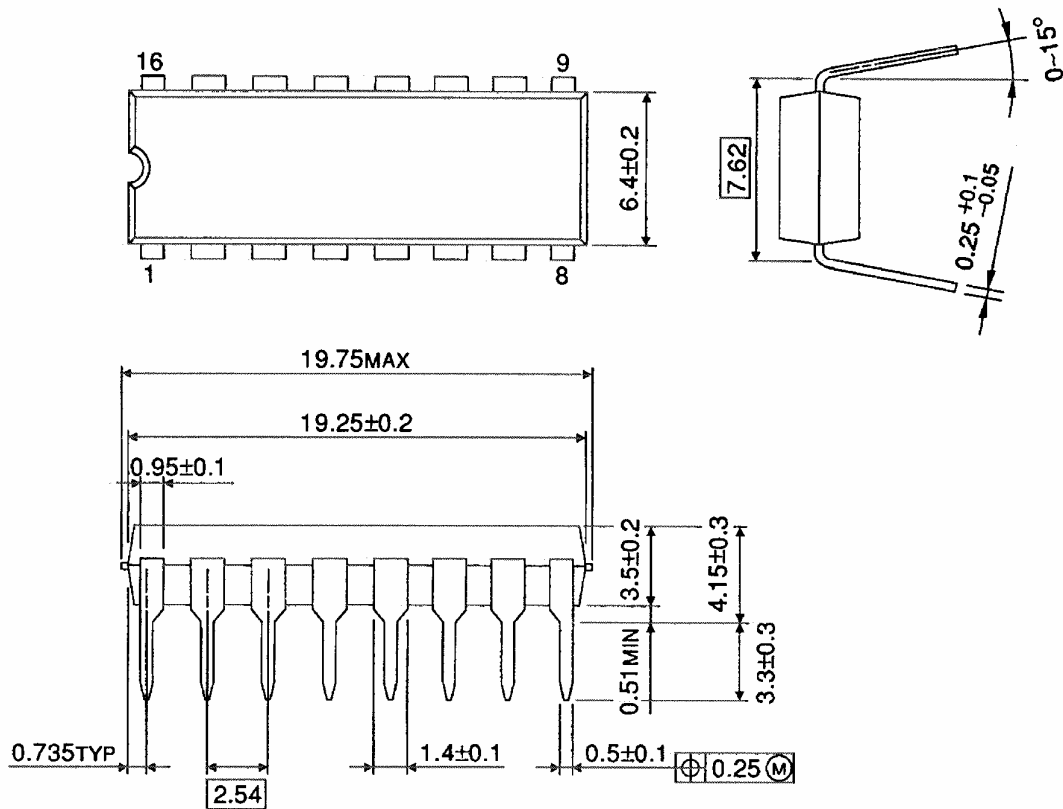
**Waveform 3**



## Package Dimensions

DIP16-P-300-2.54A

Unit : mm

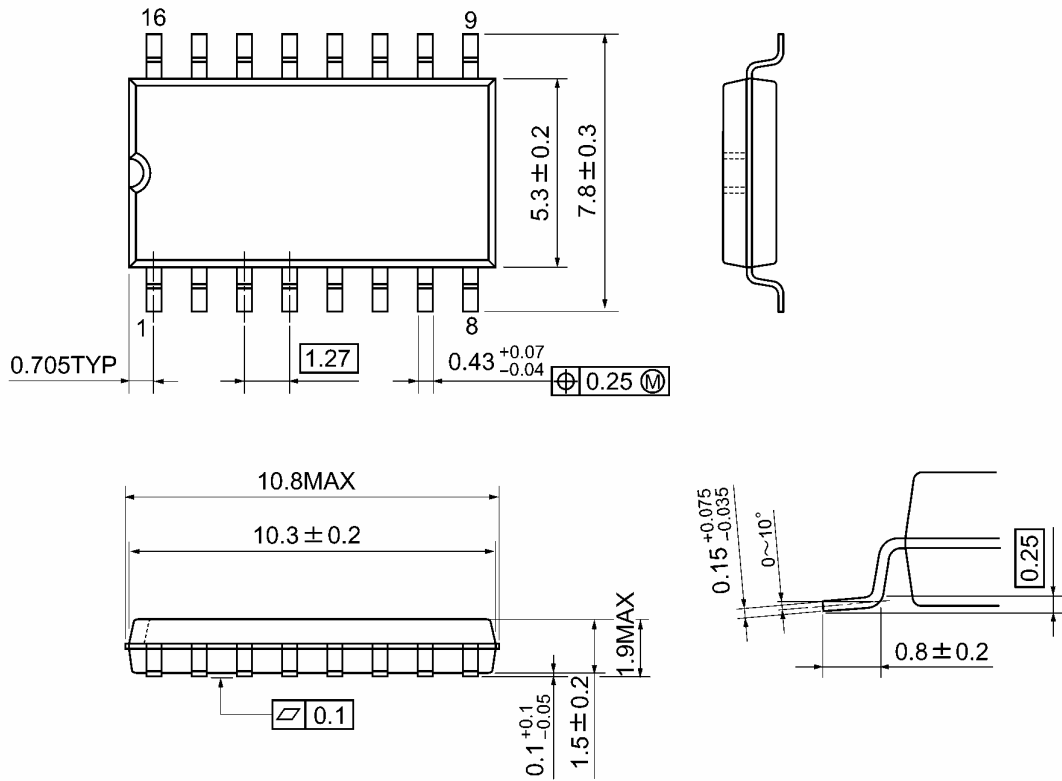


Weight: 1.00 g (typ.)

## Package Dimensions

SOP16-P-300-1.27A

Unit: mm

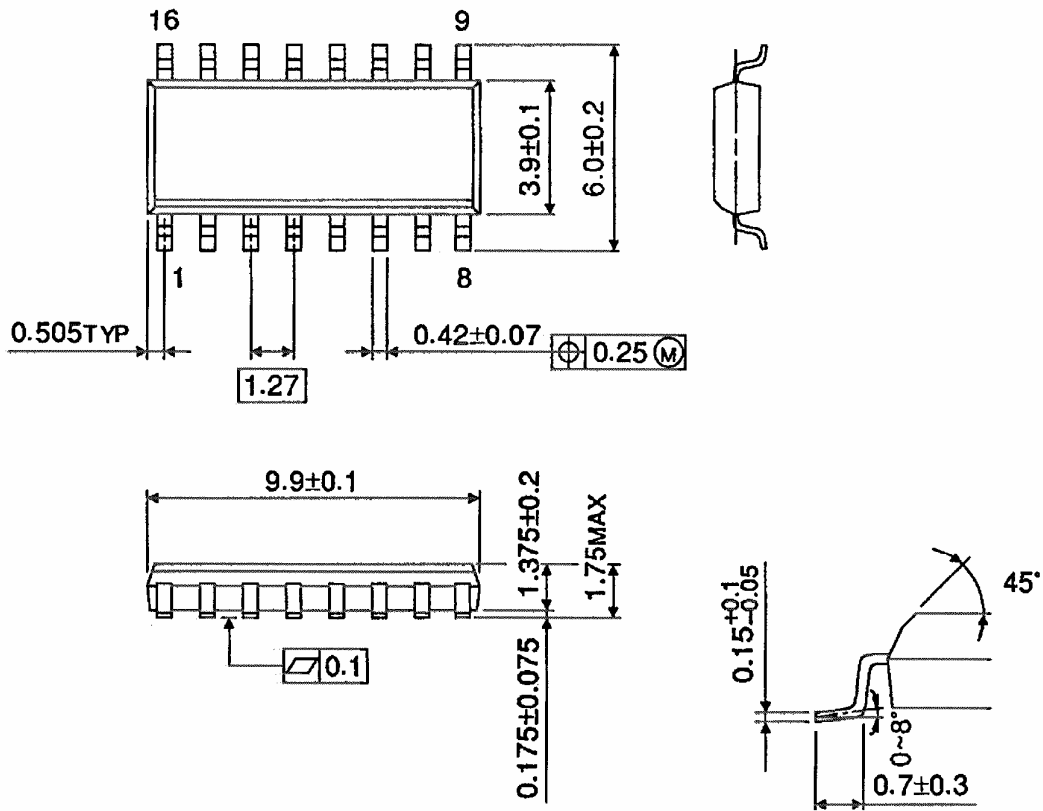


Weight: 0.18 g (typ.)

## Package Dimensions (Note)

SOL16-P-150-1.27

Unit : mm



Note: This package is not available in Japan.

Weight: 0.13 g (typ.)



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20070701-EN GENERAL

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